



NOTES/SPECIFICATIONS:

1. DESIGN WAVELENGTH: 352nm
2. CLEAR APERTURE: >80% DIAMETER
3. DIAMETER TOLERANCE: +0.0 / -0.1mm
4. THICKNESS TOLERANCE: ±0.2mm
5. SURFACE FLATNESS: $\lambda/10$ AT 632.8nm OVER CLEAR APERTURE
6. SURFACE QUALITY: 10-5 SCRATCH-DIG
7. BACK SURFACE: FINE GROUND
8. PARALLELISM: ≤ 3 arcmin
9. DURABILITY: MIL-C-675
10. COATING: REFLECTIVE COATING
Ravg>99.5%
AOI: 0°

FOR INFORMATION ONLY
NOT FOR MANUFACTURING PURPOSES

DRAWING PROJECTION			THORLABS www.thorlabs.com	
	NAME	DATE	Ø 25.4mm XeF EXCIMER MIRROR $\lambda = 352\text{nm}$, 0° AOI	
DRAWN	BAG	22/OCT/10		
APPROVAL	PM	27/OCT/10	MATERIAL	REV
COPYRIGHT © 2010 BY THORLABS			FUSED SILICA	C
VALUES IN PARENTHESIS ARE CALCULATED AND MAY CONTAIN ROUND OFF ERRORS		ITEM #	APPROX WEIGHT	
		NB1-H09	0.007 kg	